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July 2014

FDMS86202

N-Channel Shielded Gate PowerTrench[®] MOSFET 120 V, 64 A, 7.2 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 7.2 m Ω at V_{GS} = 10 V, I_D = 13.5 A
- Max $r_{DS(on)}$ = 10.3 m Ω at V_{GS} = 6 V, I_D = 11.5 A
- \blacksquare Advanced Package and Silicon combination for low $r_{\text{DS}(\text{on})}$ and high efficiency
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

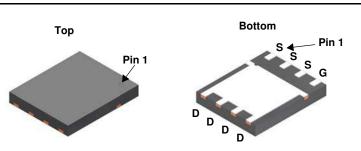
General Description

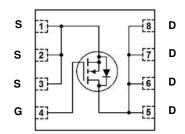
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance.

Application

■ DC-DC Conversion







Power 56

MOSFET Maximum Ratings TA = 25 °C unless otherwise noted

Symbol	Paramet	ter		Ratings	Units	
V _{DS}	Drain to Source Voltage			120	V	
V_{GS}	Gate to Source Voltage			±20	V	
I _D	Drain Current -Continuous	T _C = 25 °C		64		
	-Continuous T _A = 25		(Note 1a)	13.5	Α	
	-Pulsed		(Note 4)	240		
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	600	mJ	
Б	Power Dissipation	T _C = 25 °C		156	w	
P_{D}	Power Dissipation $T_A = 25 ^{\circ}\text{C}$ (Note 1a)			2.7	VV	
T _J , T _{STG}	Operating and Storage Junction Temperate	ure Range		-55 to +150	°C	

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case		0.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	45	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS86202	FDMS86202	Power 56	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Parameter

Off Characteristics							
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	120			V	
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		103		mV/°C	
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 96 V, V _{GS} = 0 V			1	μΑ	
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA	

Test Conditions

Min

Тур

Max

Units

On Characteristics

Symbol

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.0	3.1	4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-10		mV/°C
		$V_{GS} = 10 \text{ V}, I_D = 13.5 \text{ A}$		6.0	7.2	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 11.5 \text{ A}$		8.1	10.3	mΩ
` ,		V_{GS} = 10 V, I_D = 13.5 A, T_J = 125 °C		10.9	13.2	
9 _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 13.5 \text{ A}$		44		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V = 60 V V = 0 V		3195	4250	pF
C _{oss}	Output Capacitance	V _{DS} = 60 V, V _{GS} = 0 V, f = 1 MHz		449	600	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1011 12		17	30	pF
R_g	Gate Resistance		0.1	0.9	2.7	Ω

Switching Characteristics

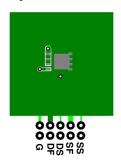
t _{d(on)}	Turn-On Delay Time			21	33	ns
t _r	Rise Time	V _{DD} = 60 V, I _D = 13.5 A,		6	13	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		27	44	ns
t _f	Fall Time			5	11	ns
Q_q	Total Gate Charge	V _{GS} = 0 V to 10 V		45	64	nC
Q_q	Total Gate Charge	$V_{GS} = 0 \text{ V to 6 V}$ $V_{DD} =$	60 V,	29	41	nC
Q _{gs}	Gate to Source Charge	I _D = 1:	3.5 A	14.3		nC
Q_{ad}	Gate to Drain "Miller" Charge			8.7		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.1 A (Note 2)	0.69	1.2	V
		$V_{GS} = 0 \text{ V}, I_S = 13.5 \text{ A}$ (Note 2)	0.76	1.3	
t _{rr}	Reverse Recovery Time	I _E = 13.5 A, di/dt = 100 A/μs	73	118	ns
Q _{rr}	Reverse Recovery Charge	1F = 13.5 A, αι/αι = 100 A/μs	117	187	nC

Notes:

^{1.} $R_{\theta JA}$ is determined with the device mounted on a 1in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 45 °C/W when mounted on a 1 in² pad of 2 oz copper



b) 115 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 $\mu\text{s},$ Duty cycle < 2.0%.
- 3. E_{AS} of 600 mJ is based on starting T_J = 25 °C, L = 3 mH, I_{AS} = 20 A, V_{DD} = 120 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 65 A.
- 4. Pulse Id limited by junction temperature, td \leq 100 μ s, please refer to SOA curve for more details.

Typical Characteristics T_{.1} = 25 °C unless otherwise noted

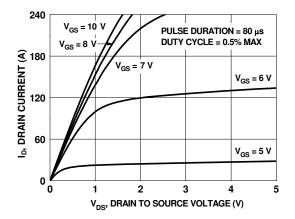


Figure 1. On Region Characteristics

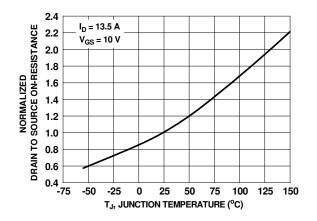


Figure 3. Normalized On Resistance vs Junction Temperature

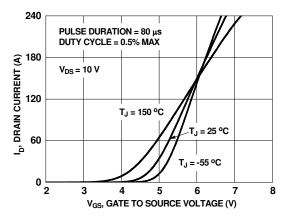


Figure 5. Transfer Characteristics

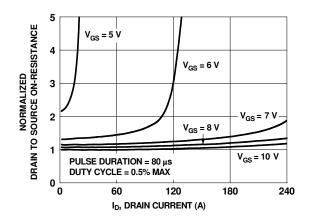


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

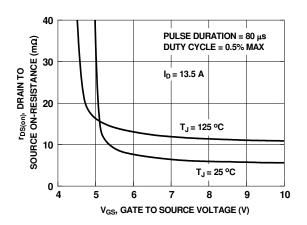


Figure 4. On-Resistance vs Gate to Source Voltage

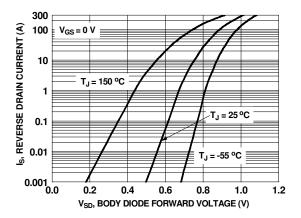


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

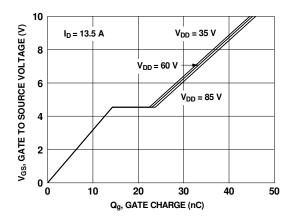


Figure 7. Gate Charge Characteristics

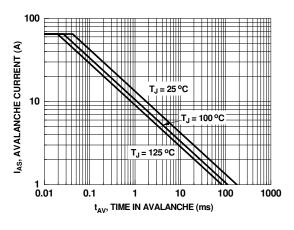


Figure 9. Unclamped Inductive Switching Capability

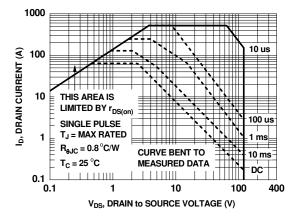


Figure 11. Forward Bias Safe Operating Area

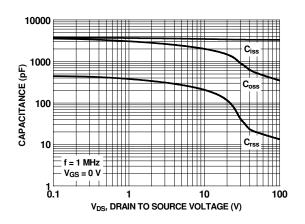


Figure 8. Capacitance vs Drain to Source Voltage

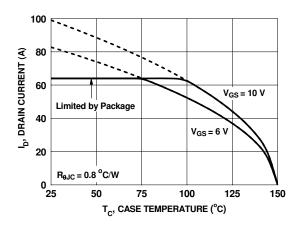


Figure 10. Maximum Continuous Drain Current vs Case Temperature

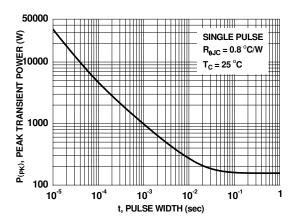


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

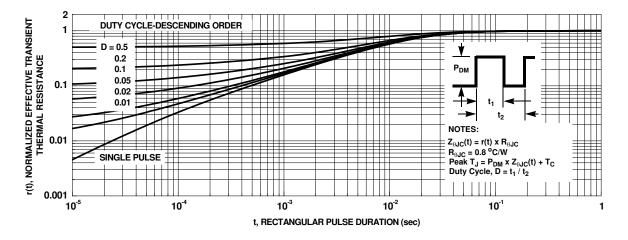
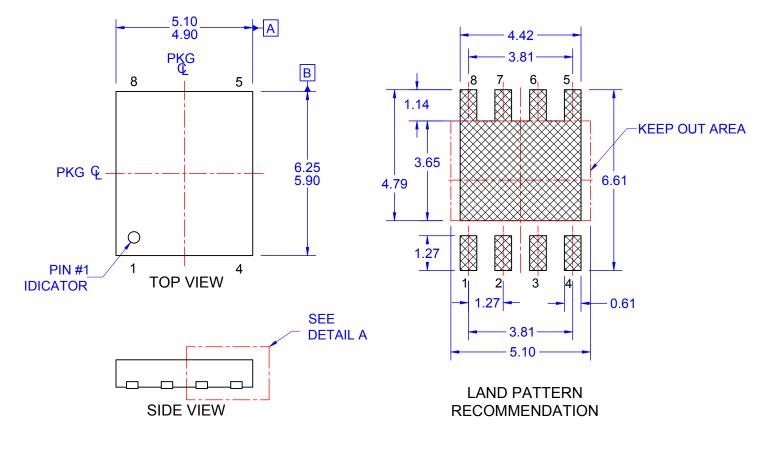
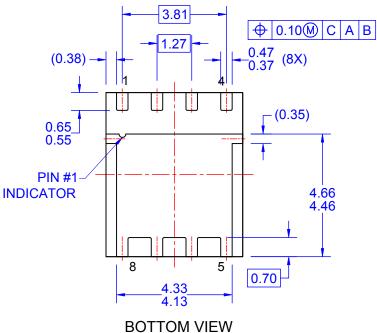
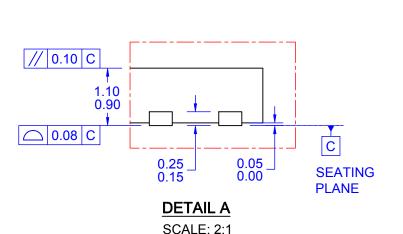


Figure 13. Junction-to-Case Transient Thermal Response Curve







NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. AA,
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2009.
- E) IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.
- F) DRAWING FILE NAME: PQFN08JREV3.



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